

## **AMENDMENTS TO THE CLAIMS**

Please make the following amendments to the specification, where ~~striketrough~~ text is to be taken to indicate deletions and underlining to indicate the addition of text.

Claim 1 (Amended): An apparatus for examining and inspecting at least one sample, in order to determine the characteristics of the sample, the apparatus comprising:

- i) a support for receiving a compact disc, the compact disc constructed of a dielectric material and having deposited on a surface thereof at least one sample;
- ii) inspection means for effecting a physical change in at least one sample, the inspection means capable of moving translationally in at least one of an X direction and a Y direction and being positioned for registration with the surface of the compact disc bearing at least one sample; and
- iii) a traversal mechanism adapted for reciprocating movement to move the sample in and out of the path of the inspection means.

Claim 2 (Original): The apparatus of claim 1 wherein the traversal mechanism is a driver having a rotatable drive mechanism that rotates the compact disc.

Claim 3 (Original): The apparatus of claim 1 wherein the traversal mechanism effectuates positional change between the sample and the compact disc in the radial direction.

Claim 4 (Original): The apparatus of claim 2 wherein the traversal mechanism effectuates positional change between the sample and the compact disc in the radial direction.

Claim 5 (Canceled)

Claim 6 (Canceled)

Claim 7 (Canceled)

Claim 8 (Canceled)

Claim 9 (Canceled)

Claim 10 (Original): A mass spectrometer incorporating the apparatus of claim 1 further comprised of an analyzer selected from the group consisting of quadrupole, time of flight (TOF), quadrupole TOF, quadrupole-quadrupole TOF (Qq TOF), triple quadrupole TOF, magnetic sector, and ion trap mass analyzers.

Claim 11 (Original): The apparatus of claim 1 further comprised of a scanning assembly that includes a plurality of ion guide rods fixed in a positioning guide, the ion guide rods defining an inlet at a first end proximate to the compact disc, an outlet at a second end proximate to an entrance to the analytical device, the positioning guide further having a lens situated within the positioning guide for allowing the passage of laser energy through the positioning guide.

Claim 12 (Original): The apparatus of claim 11 wherein the positioning guide is fixed in place.

Claim 13 (Amended) ~~The apparatus of claim 11~~

An apparatus for examining and inspecting at least one sample, in order to determine the characteristics of the sample, the apparatus comprising:

i) a support for receiving a compact disc, the compact disc being constructed of a dielectric material and having deposited on a surface thereof at least one sample;

ii) inspection means for effecting a physical change in at least one sample, the inspection means capable of moving translationally in at least one of an X direction and a Y direction and being positioned for registration with the surface of the compact disc bearing at least one sample;

iii) a traversal mechanism adapted for reciprocating movement to move the sample in and out of the path of the inspection means;

iv) a scanning assembly that includes a plurality of ion guide rods fixed in a positioning guide movable in at least one of an X direction and a Y direction, and the ion guide rods defining an inlet at a first end proximate to the compact disc; and

v) an outlet at a second end proximate to an entrance to the analytical device, the positioning guide further having a lens situated within the positioning guide for allowing the passage of laser energy through the positioning guide

wherein the positioning guide is movable in at least one of an X direction and a Y direction.

Claim 14 (Amended) ~~The apparatus of claim 11~~

An apparatus for examining and inspecting at least one sample, in order to determine the characteristics of the sample, the apparatus comprising:

i) a support for receiving a compact disc, the compact disc being constructed of a dielectric material having deposited on a surface thereof at least one sample;

ii) inspection means for effecting a physical change in at least one sample, the inspection means capable of moving translationally in at least one of an X direction and a Y direction and being positioned for registration with the surface of the compact disc bearing at least one sample;

iii) a traversal mechanism adapted for reciprocating movement to move the sample in and out of the path of the inspection means;

iv) a scanning assembly that includes a plurality of ion guide rods fixed in a positioning guide movable in at least one of an X direction and a Y direction, and the ion guide rods defining an inlet at a first end proximate to the compact disc; and

v) an outlet at a second end proximate to an entrance to the analytical device, the positioning guide further having a lens situated within the positioning guide for allowing the passage of laser energy through the positioning guide

wherein the positioning guide is movable in the X direction and the Y direction.

Claim 15 (Amended) ~~The apparatus of claim 11~~

An apparatus for examining and inspecting at least one sample, in order to determine the characteristics of the sample, the apparatus comprising:

i) a support for receiving a compact disc, the compact disc constructed of a dielectric material and having deposited on a surface thereof at least one sample;

ii) inspection means for effecting a physical change in at least one

sample, the inspection means capable of moving translationally in at least one of an X direction and a Y direction and being positioned for registration with the surface of the compact disc bearing at least one sample;

iii) a traversal mechanism adapted for reciprocating movement to move the sample in and out of the path of the inspection means.

iv) a scanning assembly that includes a plurality of ion guide rods fixed in a positioning guide, the ion guide rods defining an inlet at a first end proximate to the compact disc; and an outlet at a second end proximate to an entrance to the analytical device, the positioning guide further having a lens situated within the positioning guide for allowing the passage of laser energy through the positioning guide

wherein the positioning guide, ion guide rods, and analytical device are movable in concert in at least one of an X direction and a Y direction.

Claim 16 (Amended) The apparatus of claim ~~44~~ 13 wherein the ion guide rods are constructed of a flexible material and ~~the positioning guide and~~ the first end of the ion guide rods ~~are~~ is movable in at least one of an X direction and a Y direction.

Claim 17 (Amended) The apparatus of claim 16 ~~the~~ wherein the second end of the ion guide rods ~~are~~ is fixed in place.

Claim 18 (Amended) The apparatus of claim ~~44~~ 13 wherein the ion guide rods are constructed of a flexible material and ~~the positioning guide and~~ the first end of the ion guide rods ~~are~~ is movable in the X direction and the Y direction.

Claim 19 (Amended) The apparatus of claim 16 ~~the~~ wherein the second end of the ion guide rods ~~are~~ is fixed in place.

Claim 20 (Amended): The apparatus of claim 1 wherein digital information associated with the at least one sample is positioned on the disc.

Claim 21 (Original): The apparatus of claim 1 wherein the inspection means is further capable of examining and inspecting information stored on the surface of the compact disc.

Claim 22 (Original): The apparatus of claim 21 wherein the information is stored on the surface of the compact disc on which the sample is stored.

Claim 23 (Original): The apparatus of claim 21 further comprised of a second inspection means for examining and inspecting information stored on a surface of the compact disc that is opposite the surface on which the sample is stored.

Claim 24 (Canceled)

Claim 25 (Original): The apparatus of claim 21 wherein the information stored on the disc relates to sample identity.

Claim 26 (Original): The apparatus of claim 21 wherein the information stored on the disc relates to movement of the disc.

Claim 27 (Amended) An analytical device for determining the properties of at least one sample of material, the

analytical device comprising

a base,

a substrate constructed of a dielectric material adapted to be rotatably received

by said base, said substrate having deposited thereon at least one sample of the

material to be analyzed,

an inspection means for effecting a physical change in at least one sample, the

inspection means movably associated with said base,

a translation system capable of movement in at least one of an X direction and a

Y direction and adapted to effect a change in position between the inspection

means and the substrate, causing the inspection means to register with the at

least one sample on said substrate, at a predetermined location on said

substrate.

Claim 28 (Previously Amended) The analytical device of claim 27 wherein the analytical device is a mass spectrometer.

Claim 29 (Canceled)

Claim 30 (Previously Amended) The analytical device of claim 27 further comprised of a scanning assembly that includes a plurality of ion guide rods fixed in a positioning guide, the ion guide rods defining an inlet at a first end proximal to the compact disc, an outlet at a second end proximal to an entrance to the analytical device, the positioning guide further having a lens situated within the positioning guide for allowing the passage of laser energy through the positioning guide.

Claim 31 (Previously Amended) The analytical device of claim 30, wherein the positioning guide is fixed in place.

Claim 32 (Amended) ~~The analytical device of claim 30~~

An analytical device for determining the properties of at least one sample of material,  
the

analytical device comprising

a base,

a substrate constructed of a dielectric material adapted to be rotatably received by said base, said substrate having deposited thereon at least one sample of the material to be analyzed,

an inspection means for effecting a physical change in at least one sample, the inspection means movably associated with said base,

a translation system capable of movement in at least one of an X direction and a Y direction and adapted to effect a change in position between the inspection means and the substrate, causing the inspection means to register with the at least one sample on said substrate, at a predetermined location on said substrate;

a scanning assembly that includes a plurality of ion guide rods fixed in a positioning guide, the ion guide rods defining an inlet at a first end proximal to the compact disc; and

an outlet at a second end proximal to an entrance to the analytical device, the positioning guide further having a lens situated within the positioning guide for allowing the passage of laser energy through the positioning guide

wherein the positioning guide is movable in at least one of an X direction and a Y direction.

Claim 33 (Amended) ~~The analytical device of claim 30~~

An analytical device for determining the properties of at least one sample of material,  
the

analytical device comprising



a base,

a substrate constructed of a dielectric material adapted to be rotatably received by said base, said substrate having deposited thereon at least one sample of the material to be analyzed,

an inspection means for effecting a physical change in at least one sample, the inspection means movably associated with said base,

a translation system capable of movement in at least one of an X direction and a Y direction and adapted to effect a change in position between the inspection means and the substrate, causing the inspection means to register with the at least one sample on said substrate, at a predetermined location on said substrate;

a scanning assembly that includes a plurality of ion guide rods fixed in a positioning guide, the ion guide rods defining an inlet at a first end proximal to the compact disc; and

an outlet at a second end proximal to an entrance to the analytical device, the positioning guide further having a lens situated within the positioning guide for allowing the passage of laser energy through the positioning guide

wherein the positioning guide is movable in the X direction and the Y direction.

Claim 34 (Amended) ~~The analytical device of claim 30~~

An analytical device for determining the properties of at least one sample of material, the

analytical device comprising

a base,

a substrate constructed of a dielectric material adapted to be rotatably received by said base, said substrate having deposited thereon at least one sample of the material to be analyzed,

an inspection means for effecting a physical change in at least one sample, the inspection means movably associated with said base,

a translation system capable of movement in at least one of an X direction and a Y direction and adapted to effect a change in position between the inspection means and the substrate, causing the inspection means to register with the at least one sample on said substrate, at a predetermined location on said substrate;

a scanning assembly that includes a plurality of ion guide rods fixed in a positioning guide, the ion guide rods defining an inlet at a first end proximal to the compact disc; and

an outlet at a second end proximal to an entrance to the analytical device, the positioning guide further having a lens situated within the positioning guide for allowing the passage of laser energy through the positioning guide

wherein the positioning guide, ion guide rods, and analytical device are movable in concert in at least one of an X direction and a Y direction.

Claim 35 (Amended) The apparatus of claim ~~30~~ 32 wherein the ion guide rods are constructed of a flexible material and ~~the positioning guide and the first end of the ion guide rods are~~ is movable in at least one of an X direction and a Y direction.

Claim 36 (Amended) The apparatus of claim ~~30~~ 32 ~~the~~ wherein the second end of the ion guide rods ~~are~~ is fixed in place.

Claim 37 (Amended) The apparatus of claim ~~30~~ 32 wherein the ion guide rods are constructed of a flexible material and ~~the positioning guide and~~ the first end of the ion guide rods ~~are~~ is movable in the X direction and the Y direction.

Claim 38 (Amended) The apparatus of claim 16 ~~the~~ wherein the second end of the ion guide rods ~~are~~ is fixed in place.

Claim 39 (Original): The analytical device of claim 27 wherein digital information is associated with the at least one sample is positioned on the disc.

Claim 40 (Original): The analytical device of claim 22 wherein the inspection means is further capable of examining and inspecting the information stored on the compact disc.

Claim 41 (Original): The analytical device of claim 27 wherein the information is stored on the surface of the compact disc on which the sample is stored.

Claim 42 (Original): The analytical device of claim 27 further comprised of a second inspection means for examining and inspecting information stored on a surface of the compact disc that is opposite the surface on which the sample is stored.

Claim 43 (Canceled)

Claim 44 (Original): The analytical device of claim 27 wherein the information stored on the disc relates to sample identity.

Claim 45 (Original): The analytical device of claim 27 wherein the information stored on the disc relates to movement of the disc.

Claim 46 (Amended) A method for carrying out an inspection of a sample of a material comprising the steps of:

providing a compact disc constructed from a dielectric material;

depositing at least one sample of a material to be analyzed onto the substrate;

inspecting the sample with a laser to effect a physical change in at least one sample, probing the sample with inspection means to effect a physical change in the sample; and  
creating translational motion in at least one of an X direction and a Y direction between the inspection means and at least one sample by moving one of the substrate or the inspection means.

Claim 47 (Canceled)

Claim 48 (Canceled)

Claim 49 (Amended) An apparatus for examining and inspecting at least one sample, in order to determine the characteristics of the sample, the apparatus comprising:

- i) a support for rotatably receiving a compact disc constructed from a dielectric material, the compact disc having deposited on a surface thereof at least one sample;
- ii) an inspection means for effecting a physical change in at least one sample, the inspection means being positioned for registration with the surface of the compact disc bearing at least one sample; and
- iii) a traversal mechanism, adapted for rotational motion and translational motion in at least one of an X direction and a Y direction, and capable of moving the sample in and out of the path of the inspection means.